

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. NIP-261		SERIAL NO.	
<b>LIST OF DOCUMENTS CITED BY APPLICANT</b> <i>(Use several sheets if necessary)</i>				APPLICANT Y. TAKEZAWA et al		GROUP	
				FILING DATE February 26, 2002			
<b>U.S. PATENT DOCUMENTS</b>							
*	EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AA	AL 11-330185	11/30/99	Japan (w/ English Abstract)	H01L	21/66	<input type="checkbox"/> <input checked="" type="checkbox"/>
		AM 2000-131243	05/12/00	Japan (w/ English Abstract)	G01N	21/89	<input type="checkbox"/> <input checked="" type="checkbox"/>
		AN 11-235097	08/27/99	Japan (w/ English Abstract)	H02P	9/00	<input type="checkbox"/> <input checked="" type="checkbox"/>
		AO 9-222393	08/26/97	Japan (w/ English Abstract)	G01N	21/27	<input type="checkbox"/> <input checked="" type="checkbox"/>
	↓	AP 10-115601	05/06/98	Japan (w/ English Abstract)	G01N	29/00	<input type="checkbox"/> <input checked="" type="checkbox"/>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	↓	AR	T. Ikeda et al, "Development of the Ultrasonic Degradation Tester for Low Voltage Cables", TRANSACTIONS OF THE INSTITUTE OF ELECTRICAL ENGINEERS OF JAPAN, Vol. 120-B, No. 11, pp. 1437-1442, 2000.				
		AS					
		AT					
EXAMINER				DATE CONSIDERED			
Amir ALAVI				12-1-2004			

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	AJ						
	AK						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
#	A	AL 11-118773	04/30/99	Japan (w/ English Abstract)	G01N	29/10	<input type="checkbox"/> <input checked="" type="checkbox"/>
		AM 10-19856	01/23/98	Japan (w/ English Abstract)	G01N	29/18	<input type="checkbox"/> <input checked="" type="checkbox"/>
		AN 7-35732	02/07/95	Japan (w/ English Abstract)	G01N	29/18	<input type="checkbox"/> <input checked="" type="checkbox"/>
✓		AO 7-245869	09/19/95	Japan (w/ English Abstract)	H02H	5/10	<input type="checkbox"/> <input checked="" type="checkbox"/>
		AP					<input type="checkbox"/> <input type="checkbox"/>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AR						
	AS						
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